

APPROVED
BY
DRAFTSMAN

O.G. FIG. 3C

CLASS 714	SUBCLASS 726
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6687865

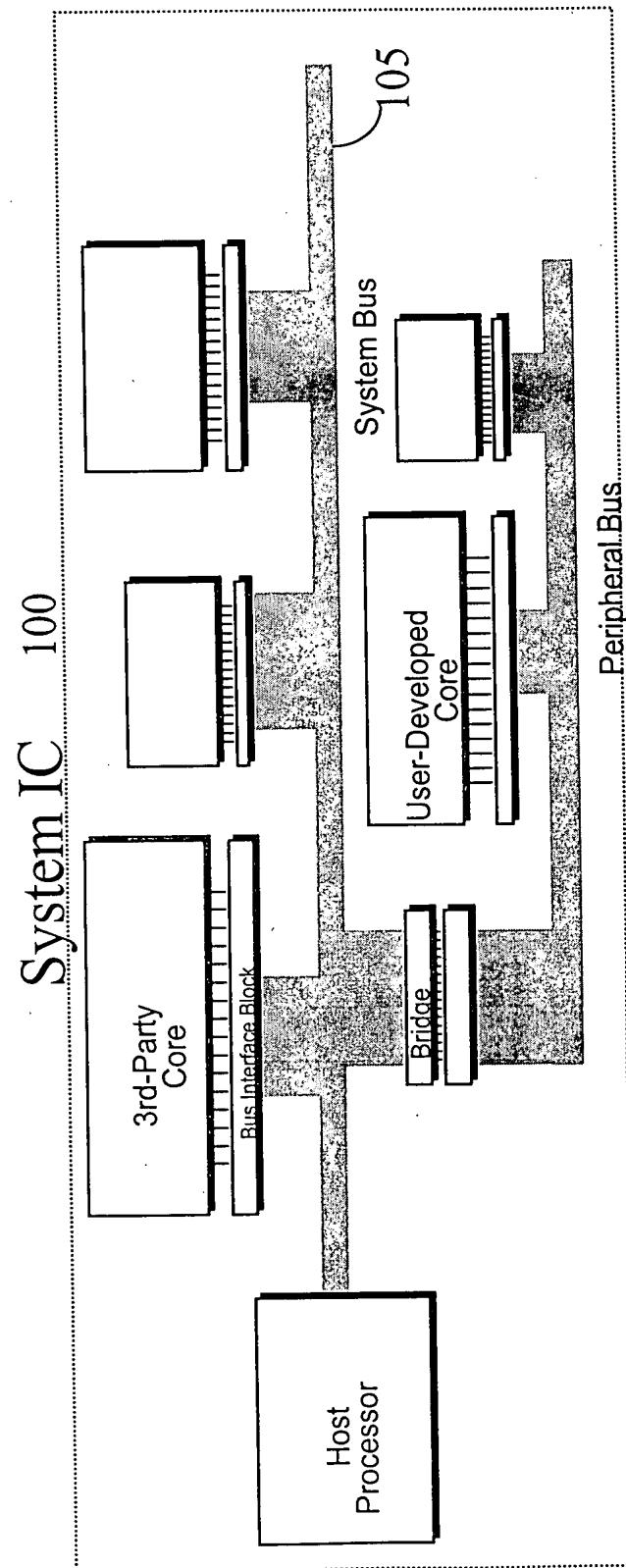


Figure 1a (prior art)

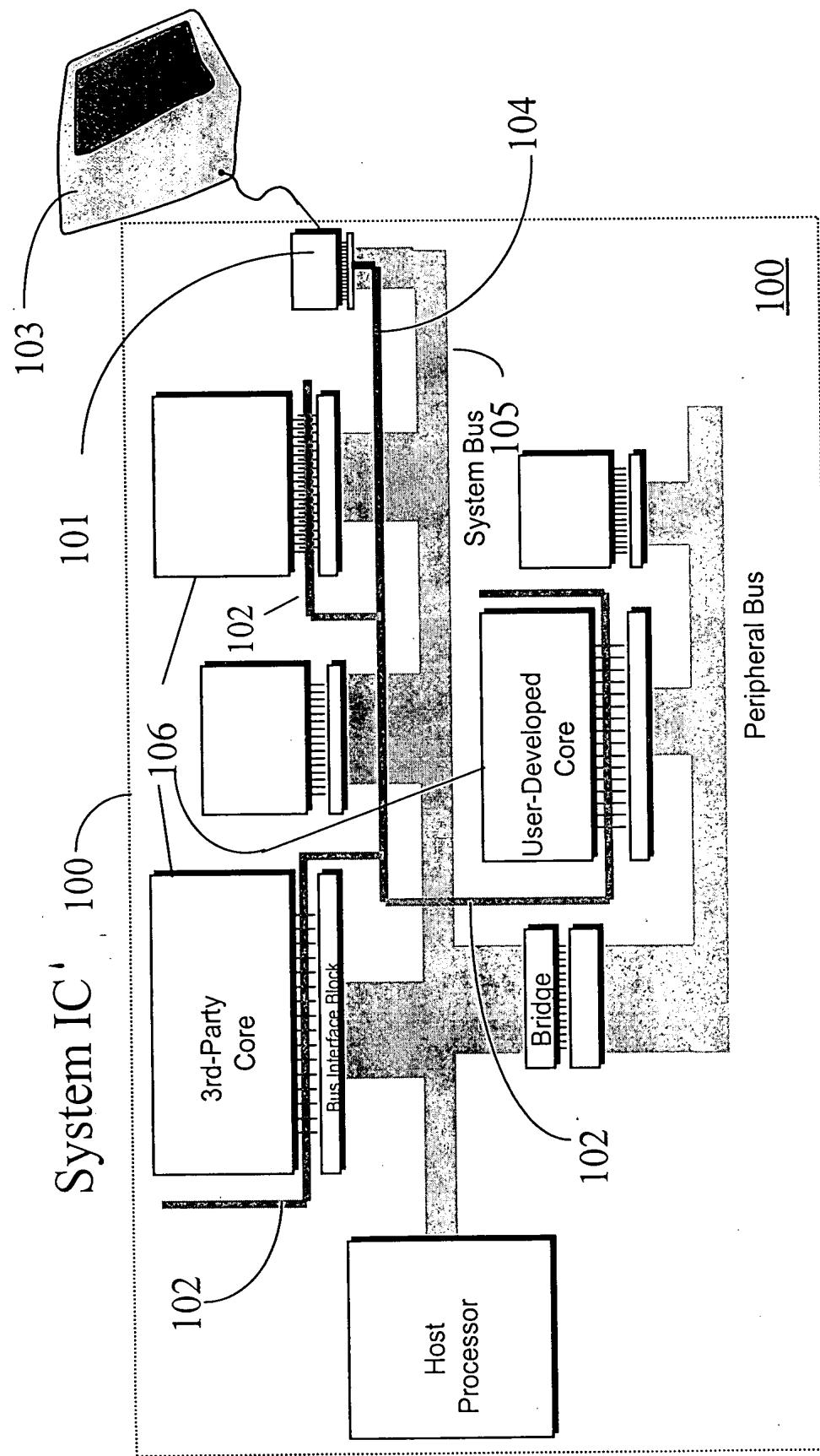


Figure 1b

APPROVED	O.G. FIG.	
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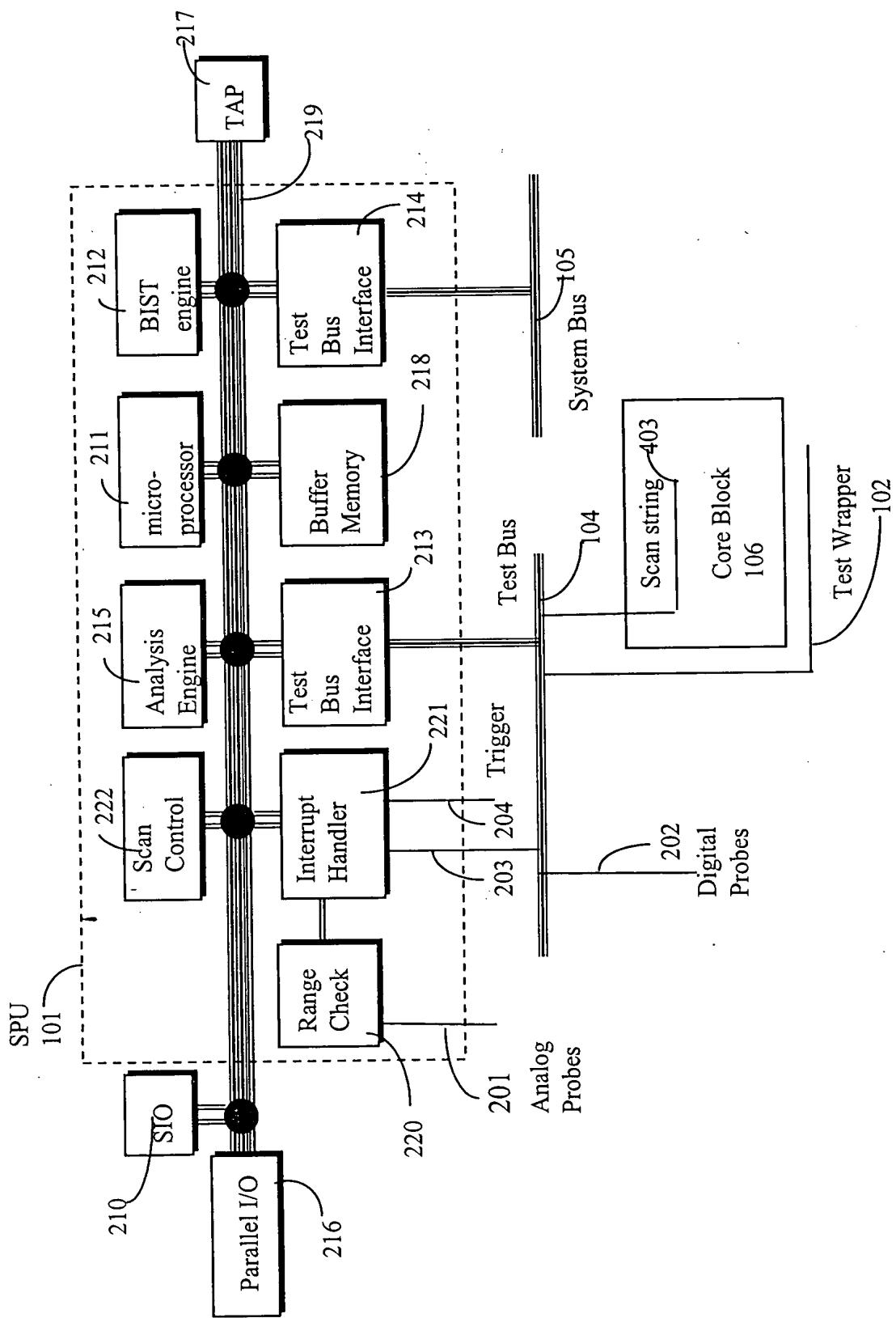


Figure 2

APPROVED	O.G. FIG.	
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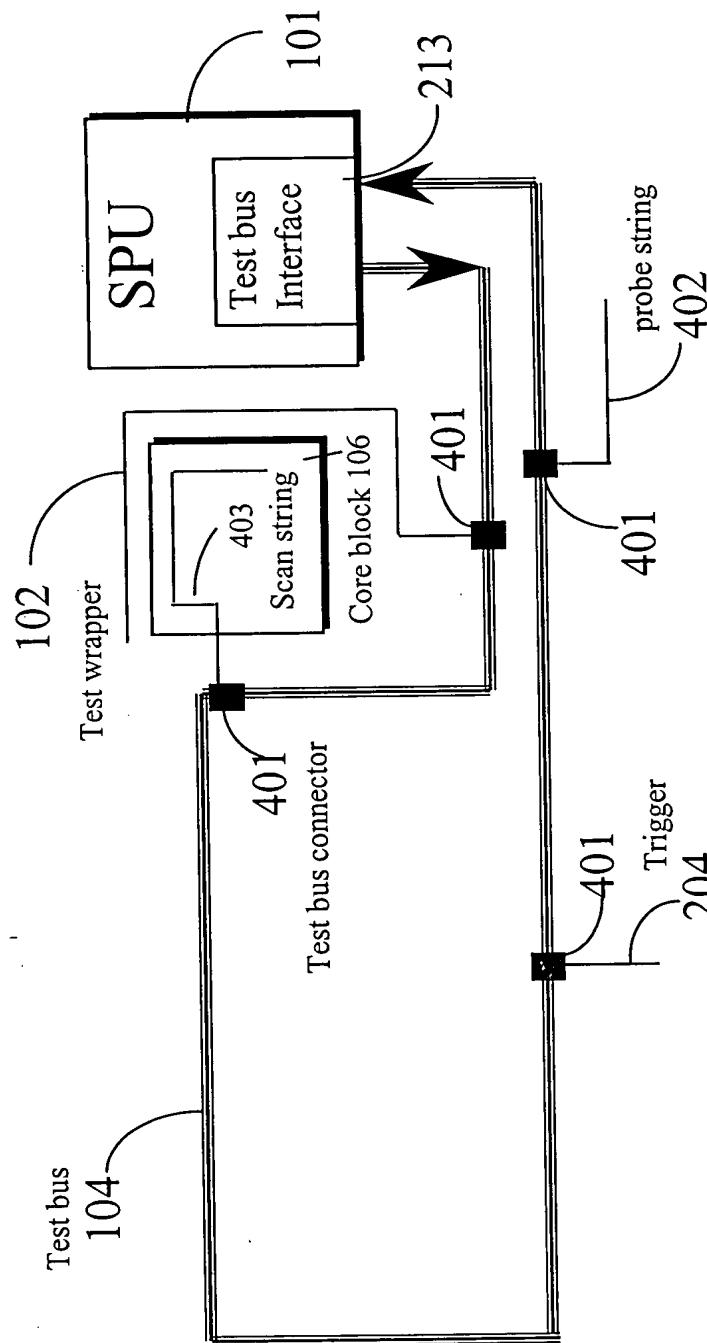


Figure 3a

APPROVED	O.G. FIG.	
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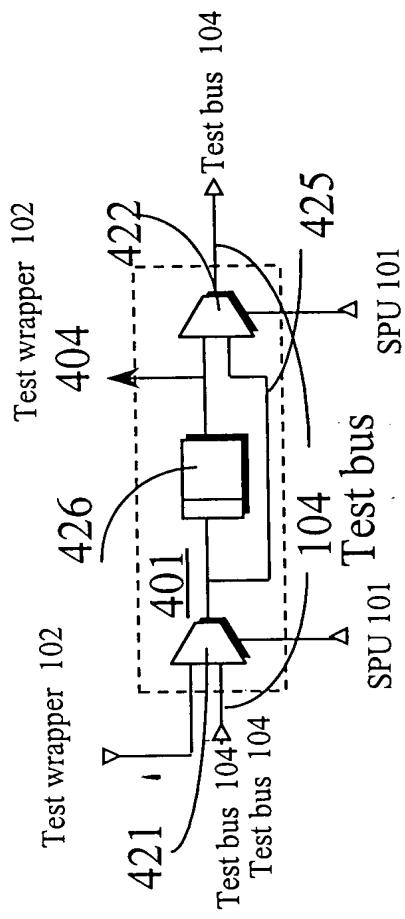


Figure 3b

Preferred Embodiment of Test Bus Connector

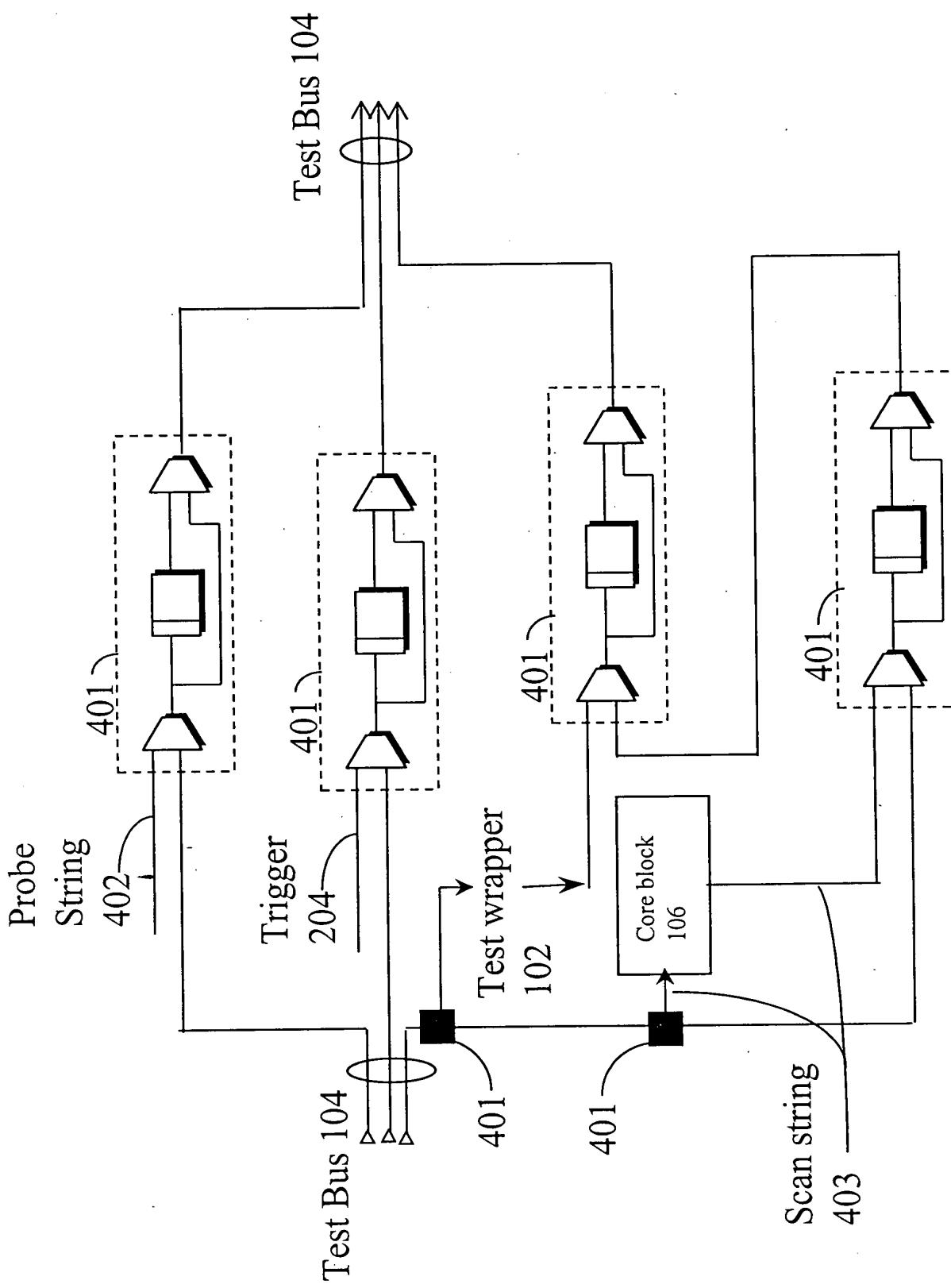


Figure 3c
Connecting Probe String, Test Wrapper or Scan String to Test Bus

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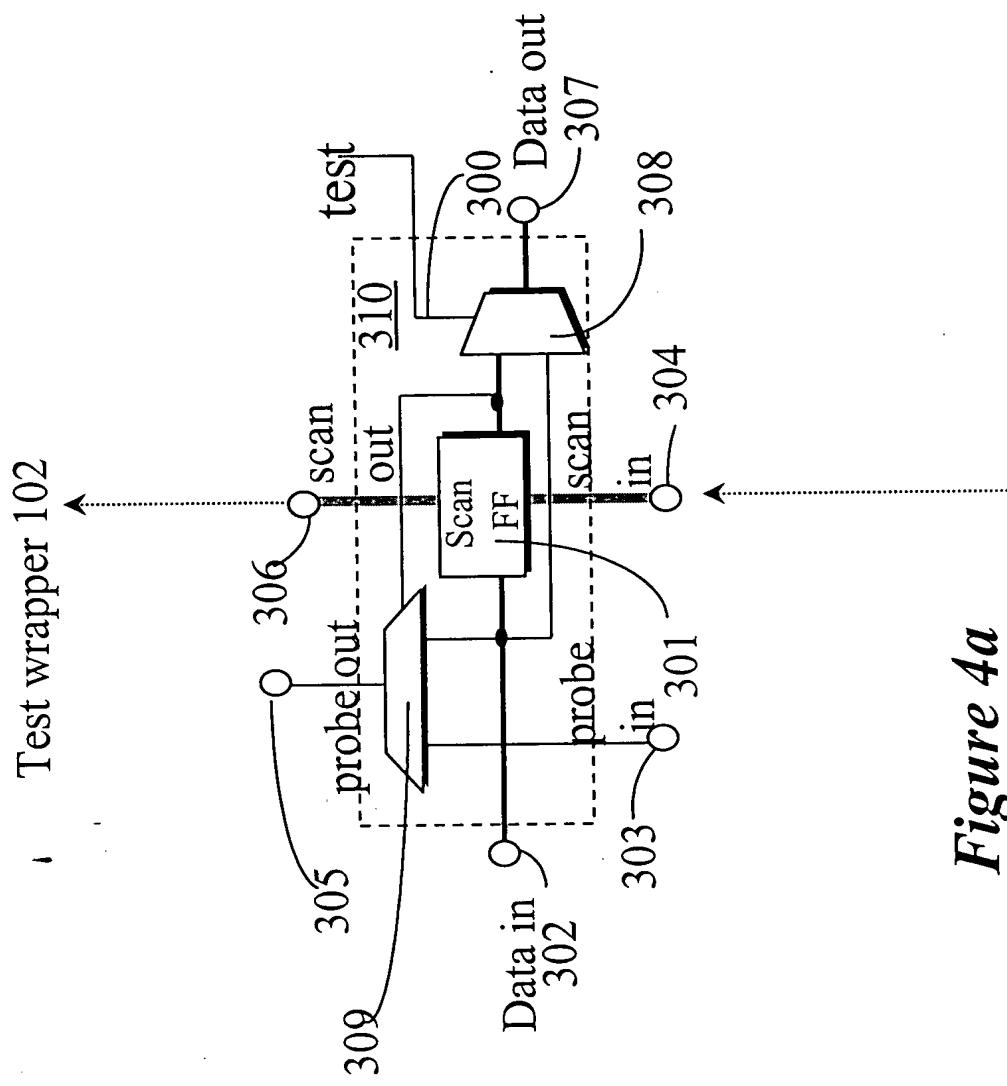


Figure 4a

Preferred Embodiment of Block Input/Output Port Connector

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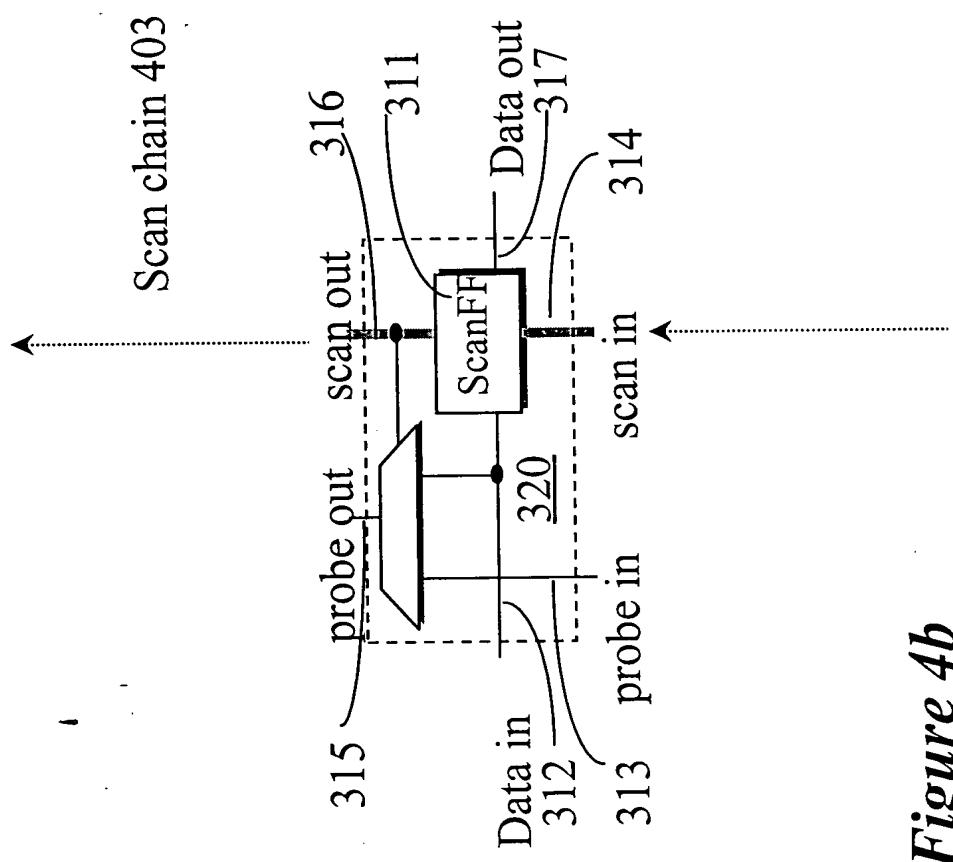


Figure 4b

Preferred Embodiment of Block Scan Connector

APPROVED	O.G. FIG.	
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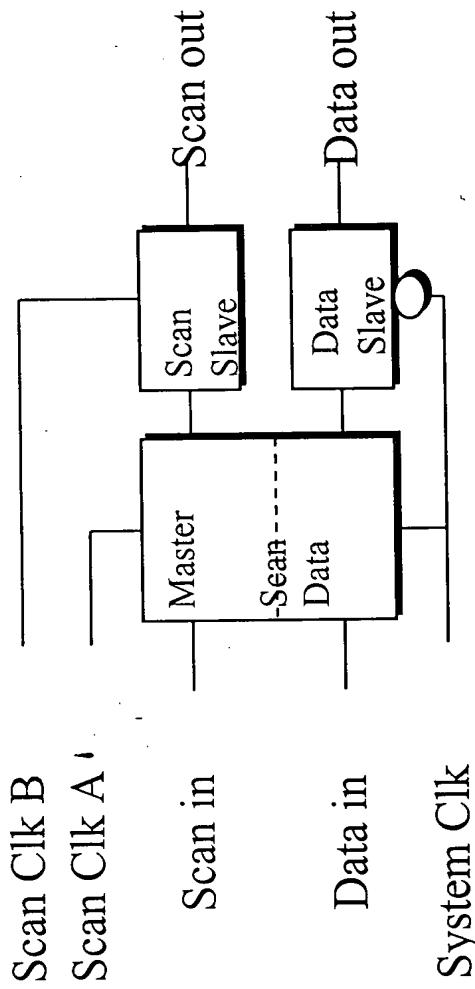


Figure 5

Internal Scan Element with Separate Scan-Slave and Data-Slave:
(prior art)

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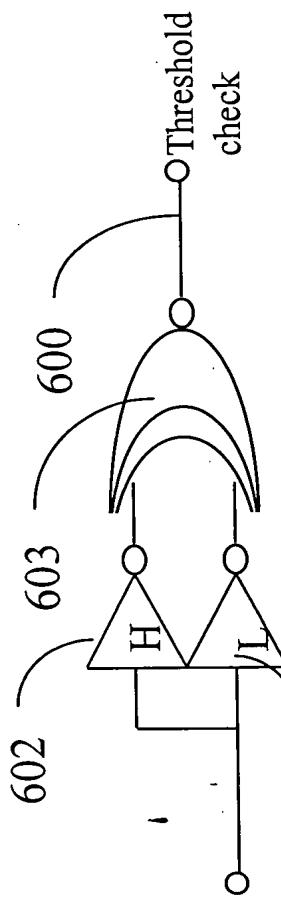


Figure 6a

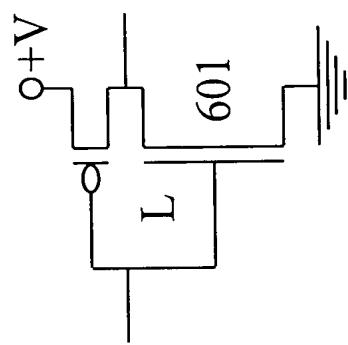


Figure 6b

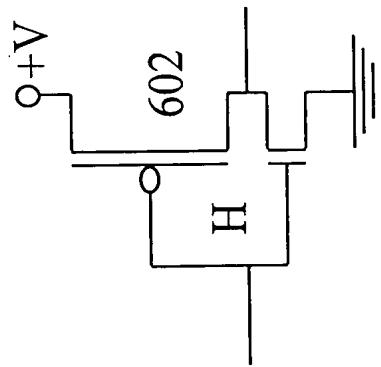


Figure 6c

APPROVED	O.G. FIG.	
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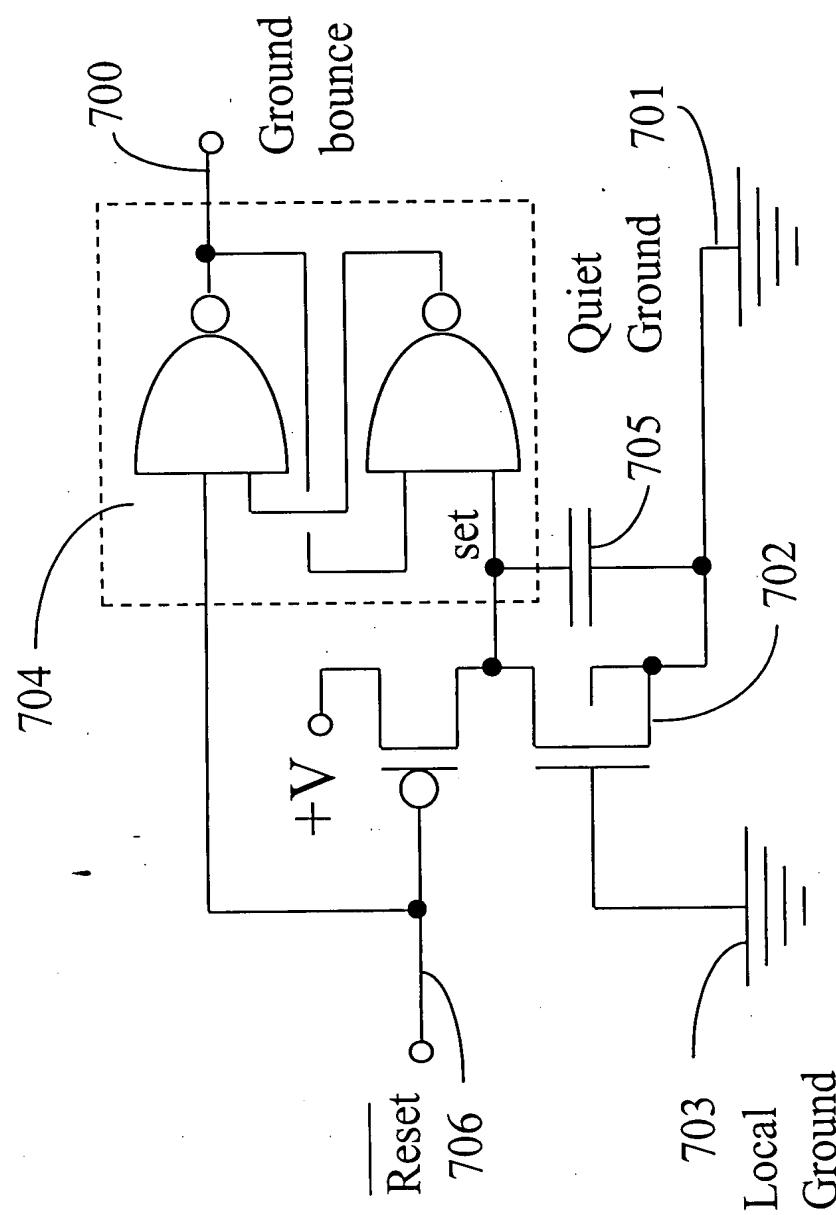


Figure 7

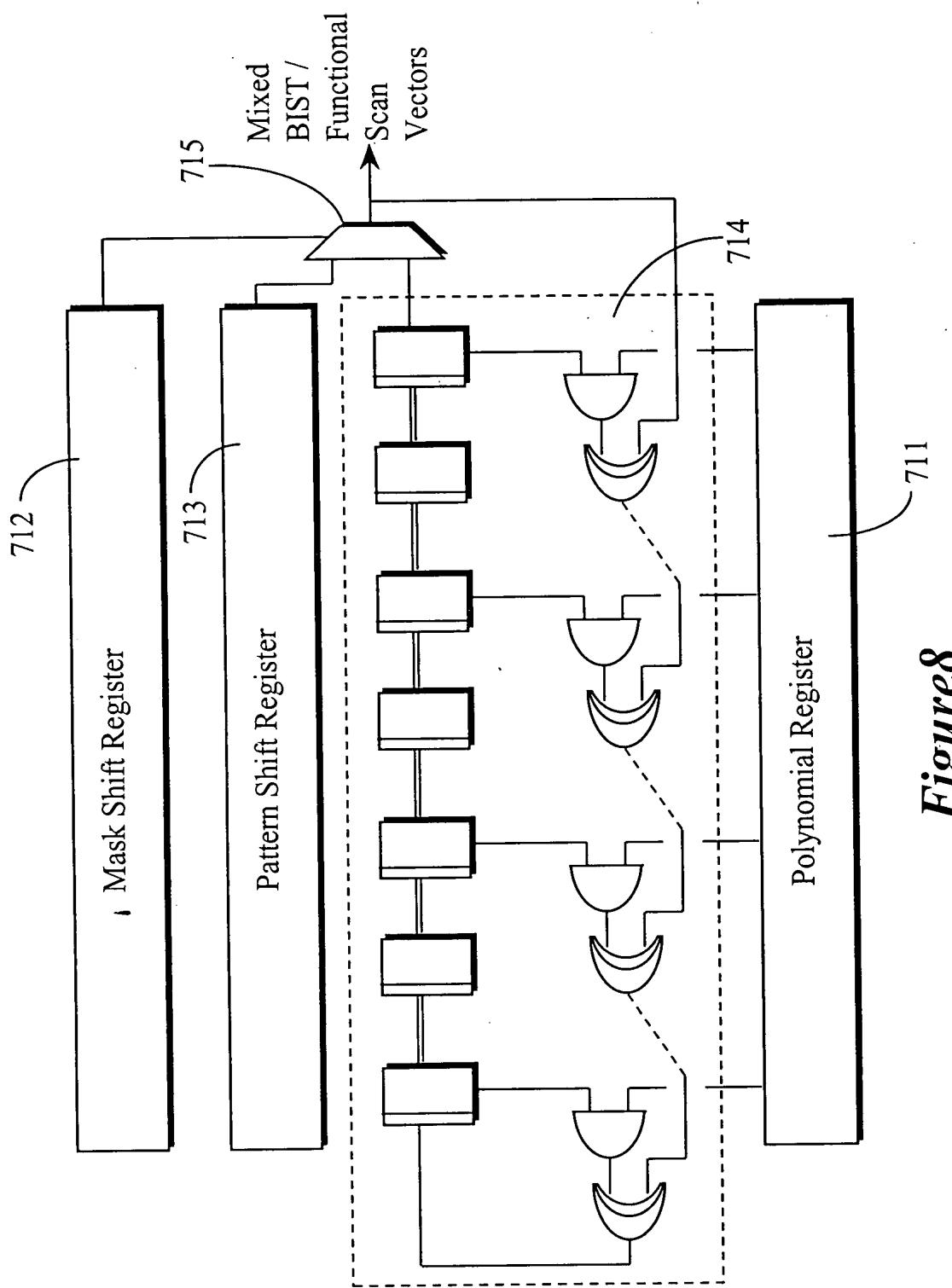


Figure 8

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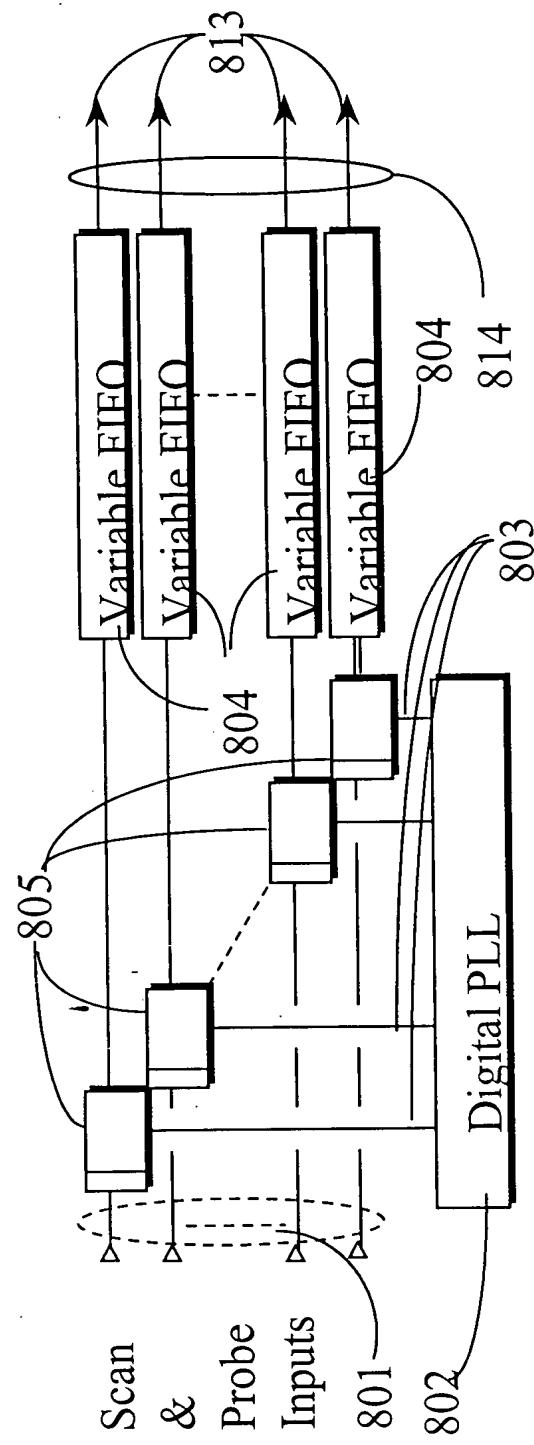


Figure 9a

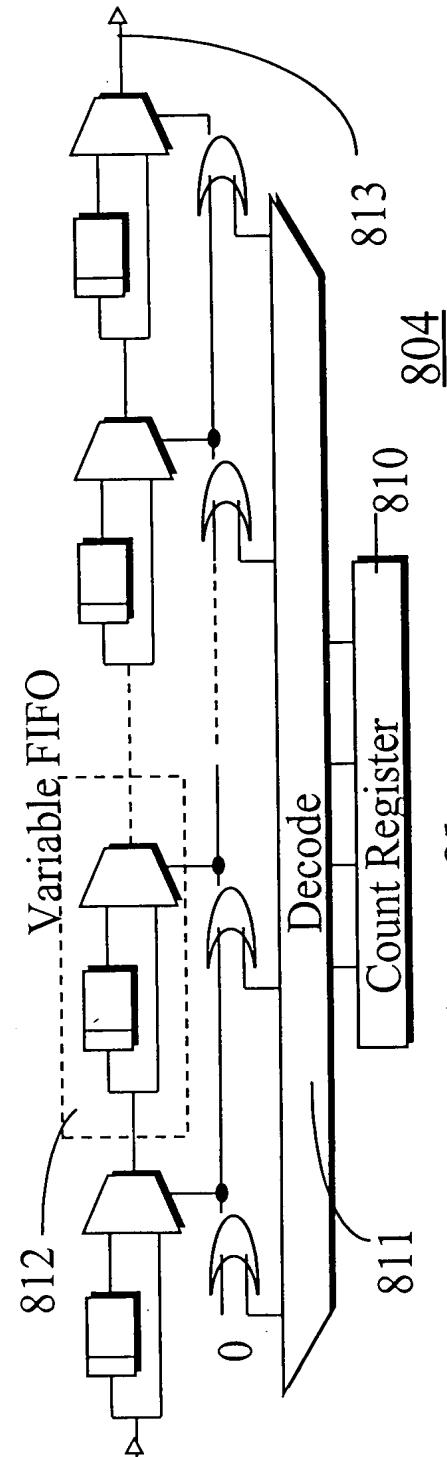


Figure 9b

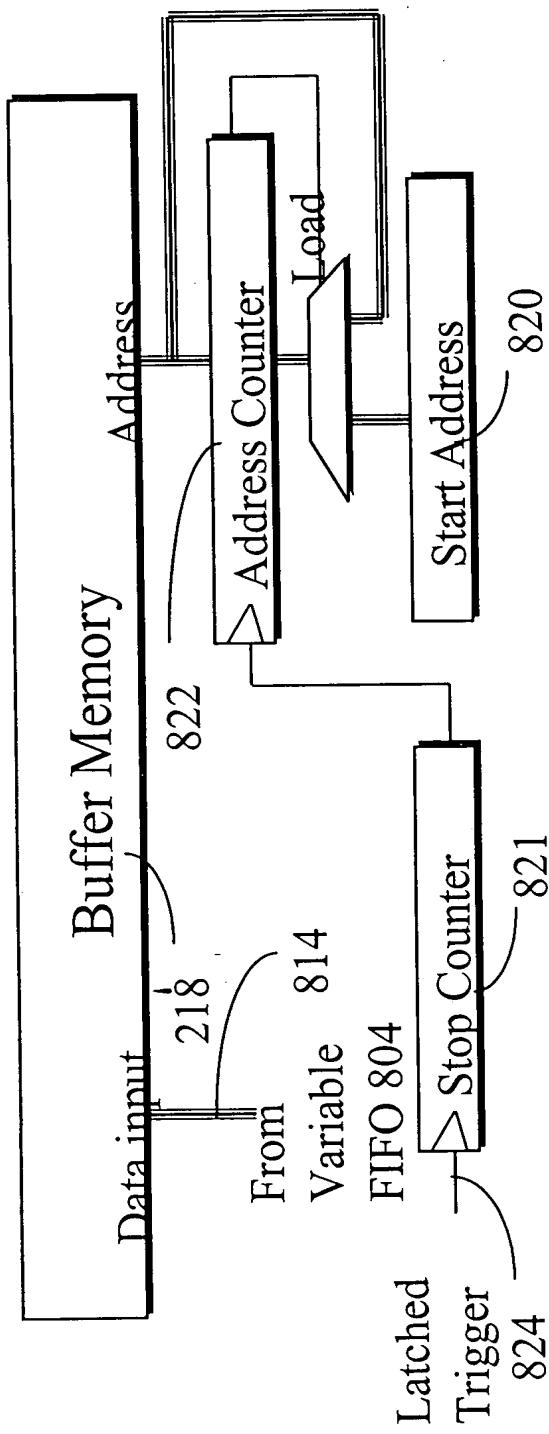


Figure 9c

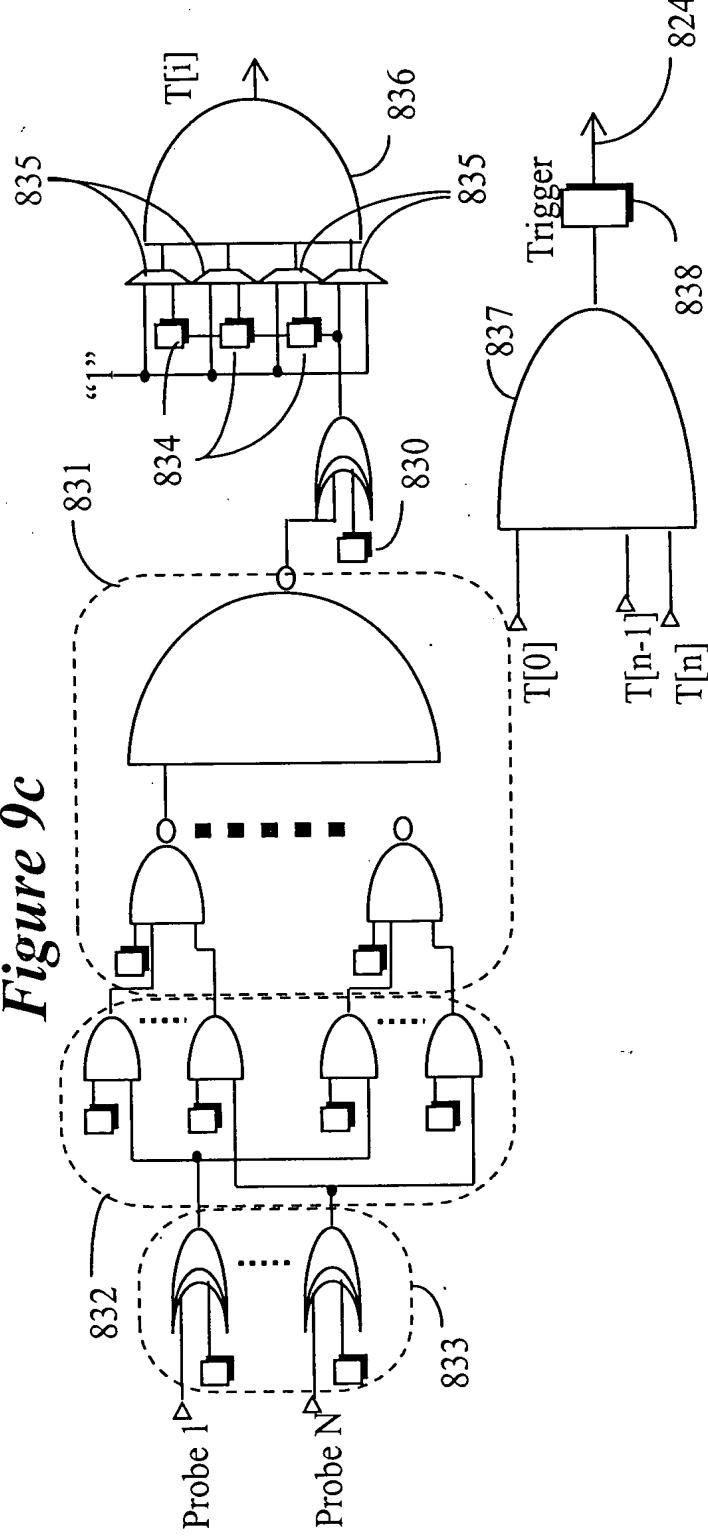


Figure 9d

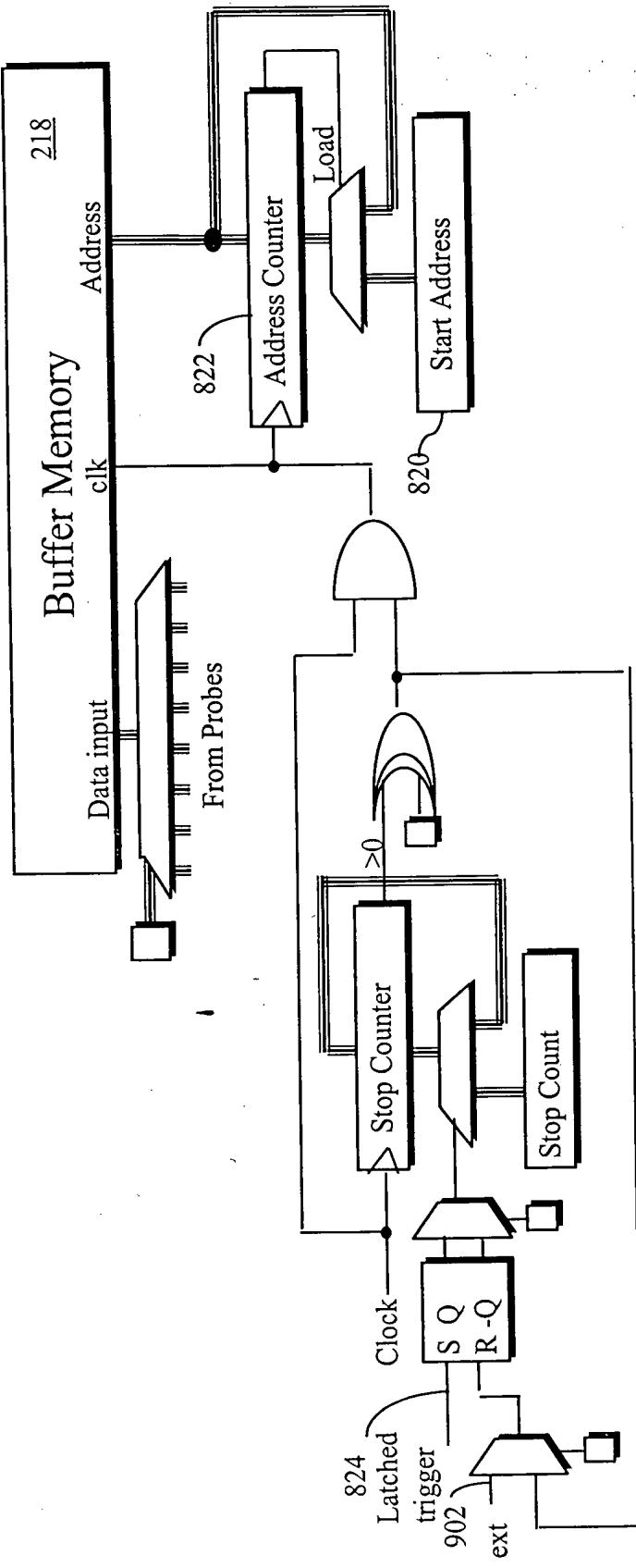


Figure 10

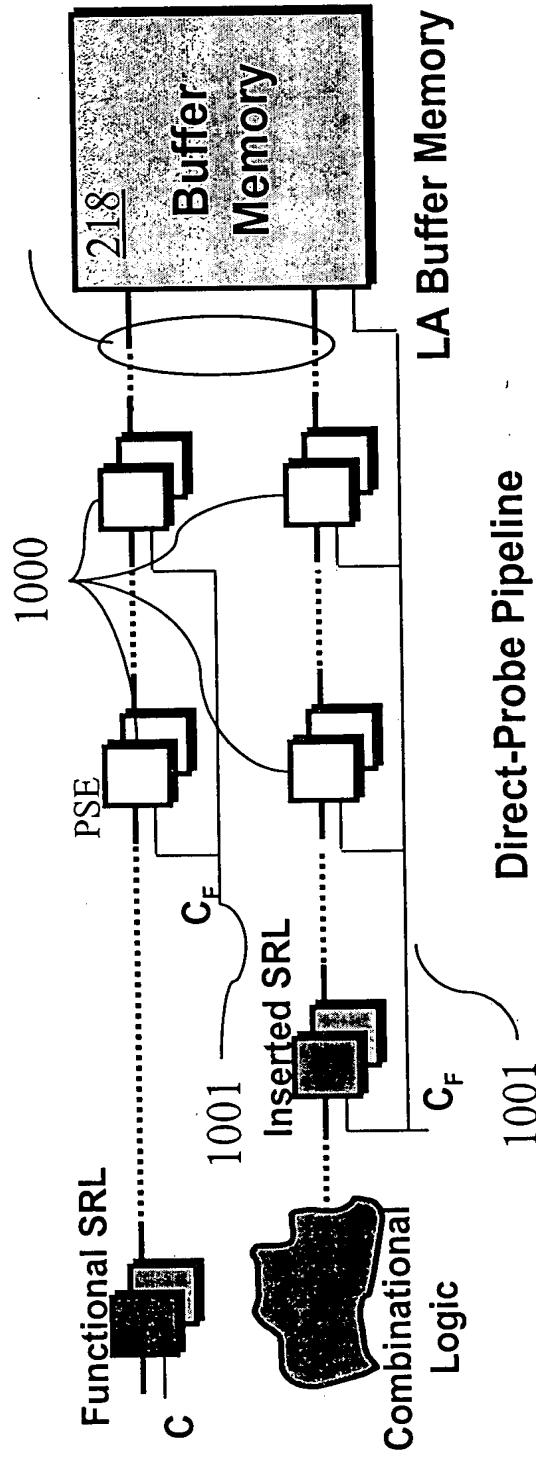
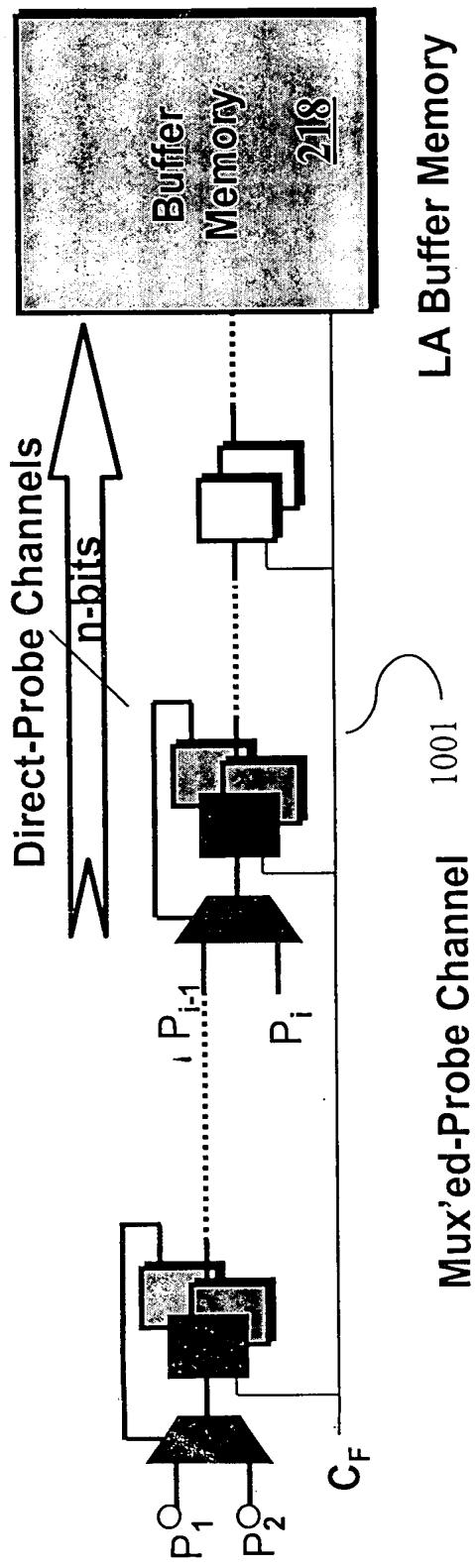


Figure 11



LA Buffer Memory

Mux'ed-Probe Channel

Figure 12

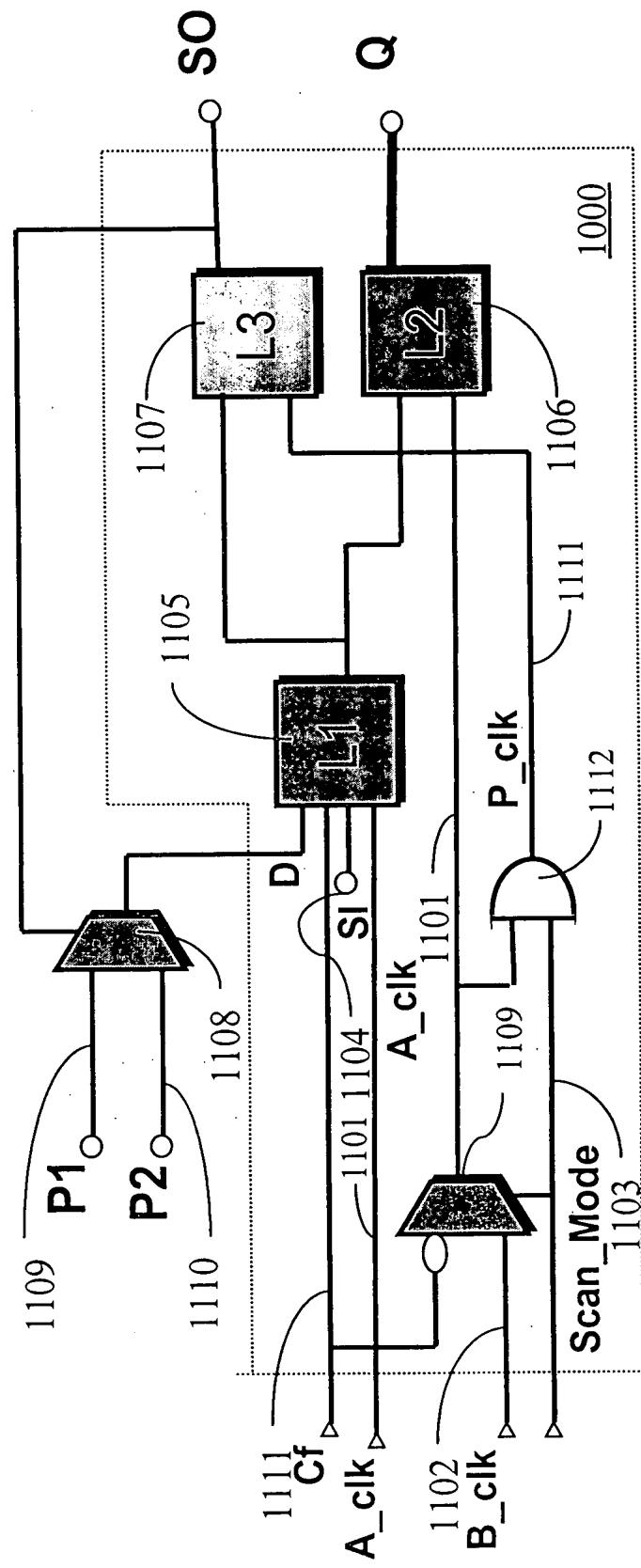


Figure 13